Product data sheet

1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a SOT186A (TO-220F) "full pack" plastic package intended for use in applications requiring high bidirectional blocking voltage capability and high thermal cycling performance.

2. Features and benefits

- High bidirectional blocking voltage capability
- High thermal cycling performance
- Isolated mounting base package
- Planar passivated for voltage ruggedness and reliability

3. Applications

- Capacitive Discharge Ignition (CDI)
- Crowbar protection
- Inrush protection
- Motor control
- Voltage regulation

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DRM}	repetitive peak off- state voltage		-	-	800	V
V_{RRM}	repetitive peak reverse voltage		-	-	800	V
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5	-	-	100	А
I _{T(RMS)}	RMS on-state current	half sine wave; $T_h \le 69$ °C; Fig. 1; Fig. 2; Fig. 3	-	-	12	А
Static charact	eristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$	-	2	15	mA





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5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	mb	A
2	Α	anode		G sym037
3	G	gate		·
mb	n.c.	mounting base; isolated		
			1 2 3	
			TO-220F (SOT186A)	

6. Ordering information

Table 3. Ordering information

Type number	Package	ackage							
	Name	Description	Version						
BT151X-800C	TO-220F	plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 "full pack"	SOT186A						

7. Limiting values

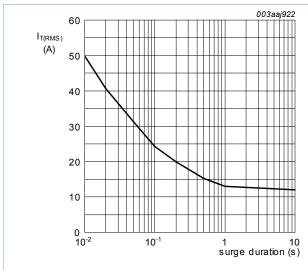
Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	800	V
V_{RRM}	repetitive peak reverse voltage		-	800	V
I _{T(AV)}	average on-state current	half sine wave; T _h ≤ 69 °C	-	7.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; $T_h \le 69$ °C; Fig. 1; Fig. 2; Fig. 3	-	12	Α
I _{TSM}	non-repetitive peak on-state current	half sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$; $t_p = 10 \text{ms}$; Fig. 4; Fig. 5	-	100	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 8.3 \text{ ms}$	-	120	A
I ² t	I ² t for fusing	t _p = 10 ms; SIN	-	50	A ² s
dl _T /dt	rate of rise of on-state current	$I_T = 20 \text{ A}; I_G = 50 \text{ mA}; dI_G/dt = 50 \text{ mA}/$ µs	-	50	A/µs
I _{GM}	peak gate current		-	2	Α

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Symbol	Parameter	Conditions	Min	Max	Unit
V_{RGM}	peak reverse gate voltage		-	5	V
P_{GM}	peak gate power		-	5	W
P _{G(AV)}	average gate power	over any 20 ms period	-	0.5	W
T _{stg}	storage temperature		-40	150	°C
Tj	junction temperature		-	125	°C



16 003aaj923
IT(RMS)
(A)
12

8

4

0
-50
0
50
100
Th (°C)

Fig. 1. RMS on-state current as a function of surge duration; maximum values

Fig. 2. RMS on-state current as a function of heatsink temperature; maximum values

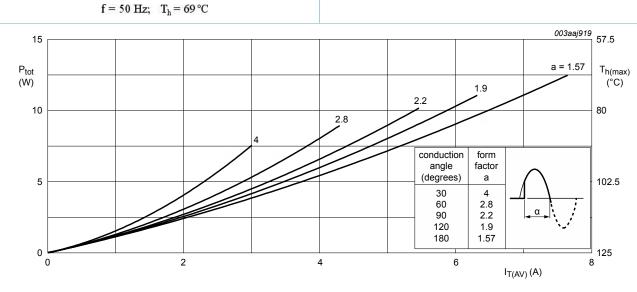


Fig. 3. Total power dissipation as a function of average on-state current; maximum values

 $\alpha = \text{conduction angle} \hspace{0.5cm} \textbf{a} = \textbf{form factor} = \textbf{I}_{T(RMS)} \: / \: \textbf{I}_{T(AV)}$

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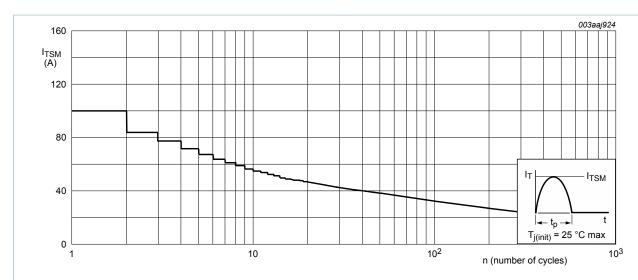


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

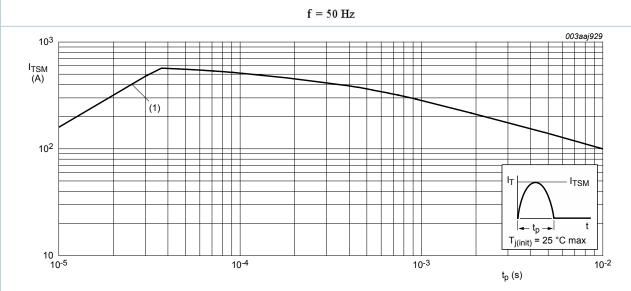


Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

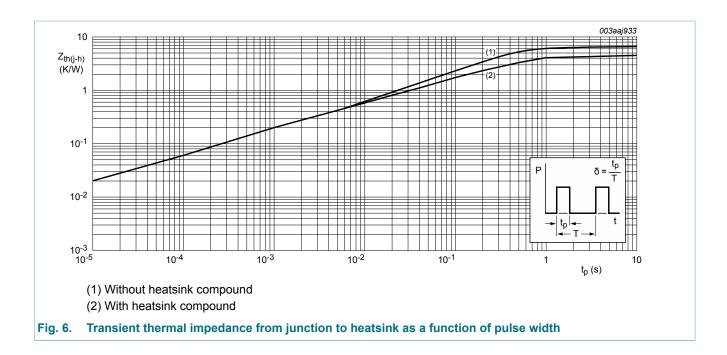
 $t_p \! \leq 10 \ ms; \ \ (1) \ \ dI_T/\,dt \ \ limit$

8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
R _{th(j-h)}	thermal resistance	with heatsink compound; Fig. 6	-	-	4.5	K/W	
from junction to heatsink		without heatsink compound; Fig. 6		-	-	6.5	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	in free air		-	55	-	K/W
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9. Isolation characteristics

Table 6. Isolation characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	from all terminals to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz \leq f \leq 60 Hz; RH \leq 65 %; T _h = 25 °C	-	-	2500	V
C _{isol}	isolation capacitance	from anode to external heatsink; f = 1 MHz; T _h = 25 °C	-	10	-	pF

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics		'			
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 7</u>	-	2	15	mA
I _L	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 8$	-	10	40	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	7	20	mA
V _T	on-state voltage	I _T = 23 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.4	1.75	V
V_{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11	-	0.6	1	V
		V _D = 800 V; I _T = 0.1 A; T _j = 125 °C; Fig. 11	0.25	0.4	-	V

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I _D	off-state current	V _D = 800 V; T _j = 125 °C	-	0.1	0.5	mA
I _R	reverse current	V _R = 800 V; T _j = 125 °C	-	0.1	0.5	mA
Dynamic cl	haracteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; R_{GK} = 100 Ω; (V_{DM} = 67% of V_{DRM}); exponential waveform; Fig. 12	200	1000	-	V/µs
		V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 12	50	130	-	V/µs
t _{gt}	gate-controlled turn-on time	I_{TM} = 40 A; V_D = 800 V; I_G = 100 mA; dI_G/dt = 5 A/ μ s; T_j = 25 °C	-	2	-	μs
t _q	commutated turn-off time	V_{DM} = 536 V; T_j = 125 °C; I_{TM} = 20 A; V_R = 25 V; $(dI_T/dt)_M$ = 30 A/μs; dV_D/dt = 50 V/μs; R_{GK} = 100 Ω; $(V_{DM}$ = 67% of $V_{DRM})$	-	70	-	μs

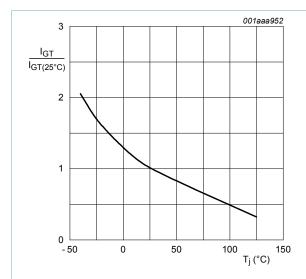
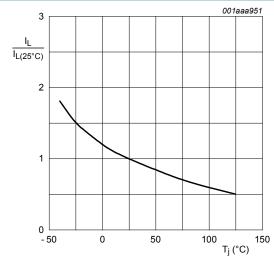


Fig. 7. Normalized gate trigger current as a function of junction temperature



8. Normalized latching current as a function of junction temperature

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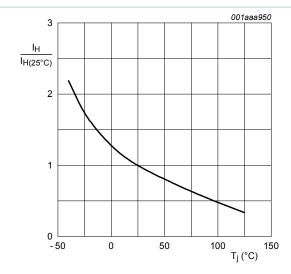
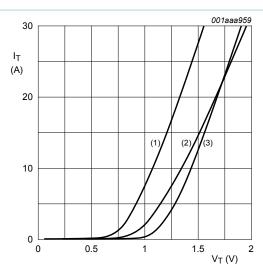


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o = 1.06 \text{ V}; R_s = 0.0304 \Omega$

(1) T_j = 125 °C; typical values

(2) T_i = 125 °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

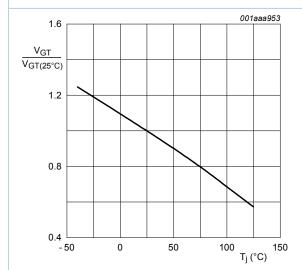
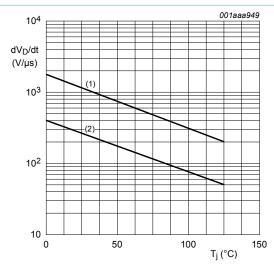


Fig. 11. Normalized gate trigger voltage as a function of junction temperature



(1) $R_{GK} = 100 \Omega$;

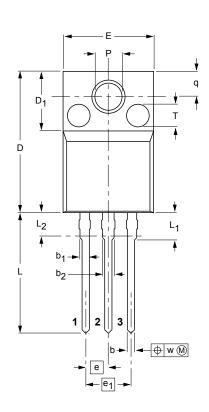
(2) gate open circuit

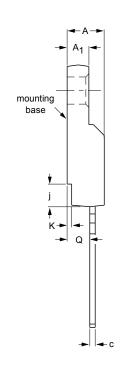
Fig. 12. Critical rate of rise of off-state voltage as a function of junction temperature; minimum values

11. Package outline

Plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 'full pack'

SOT186A





0 5 10 mm L....scale

DIMENSIONS (mm are the original dimensions)

UNIT	Α	A ₁	b	b ₁	b ₂	С	D	D ₁	E	е	e ₁	j	к	L	L ₁	L ₂ ⁽¹⁾ max.	Р	Q	q	T ⁽²⁾	w
mm	4.6 4.0	2.9 2.5	0.9 0.7	1.1 0.9	1.4 1.0	0.7 0.4	15.8 15.2	6.5 6.3	10.3 9.7	2.54	5.08	2.7 1.7	0.6 0.4	14.4 13.5	3.30 2.79	3	3.2 3.0	2.6 2.3	3.0 2.6	2.5	0.4

Notes

- 1. Terminal dimensions within this zone are uncontrolled.
- 2. Both recesses are # 2.5×0.8 max. depth

OUTLINE		EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT186A		3-lead TO-220F			-02-04-09 06-02-14

Fig. 13. Package outline TO-220F (SOT186A)

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